

SERIAL E<sup>2</sup>PROM  
**TC89121P, TC89122P**  
**TC89121M, TC89122M**

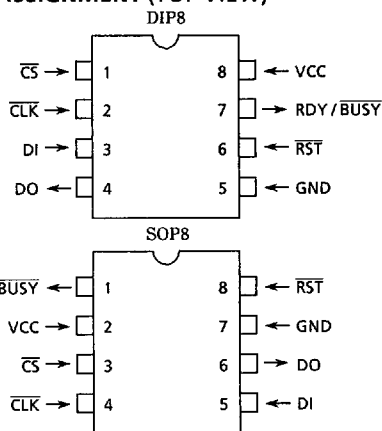
The TC89121P is a 1024 bit serial E<sup>2</sup>PROM. The TC89122P is a 2048 bit serial E<sup>2</sup>PROM. These are fabricated with floating gate CMOS technology.

PART No.	CAPACITY	ORGANIZATION	PACKAGE
TC89121P	1024-bit	128 x 8-bit	DIP8
TC89121M			SOP8
TC89122P	2048-bit	256 x 8-bit	DIP8
TC89122M			SOP8

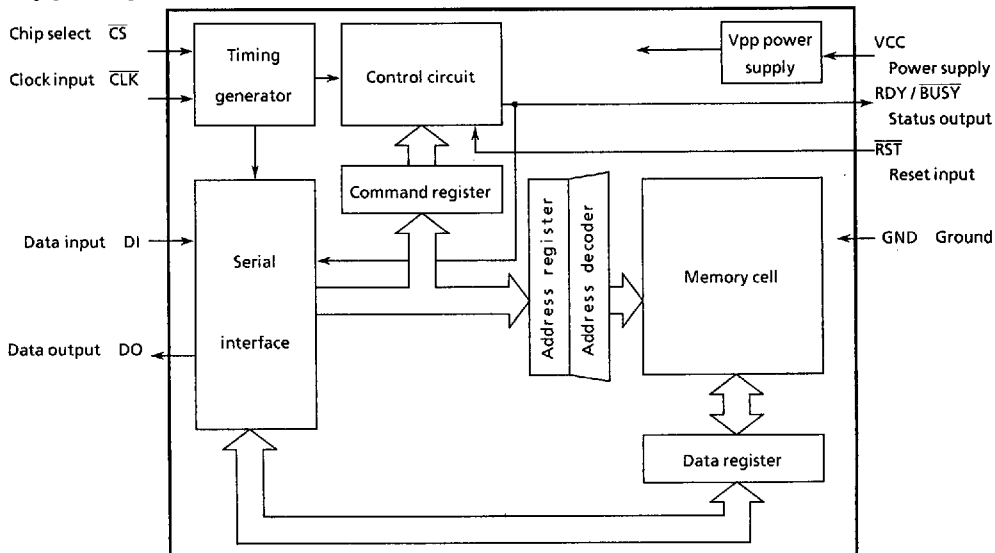
**FEATURES**

- ◆ Serial I/O
- ◆ Self timed Program cycle (Built in Timer)
- ◆ Program Time ; 10ms Max (Vcc 2.7 to 5.5V)
- ◆ Ready/Busy status signal
- ◆ Erase/Write Enable and Disable by software
- ◆ Program and Chip Erase
- ◆ Single 5V supply
- ◆ Low power dissipations (CMOS)
- ◆ Wide voltage supply (2.7 to 5.5V)
- ◆ Wide operating temperature

**PIN ASSIGNMENT (TOP VIEW)**



**BLOCK DIAGRAM**



## PIN FUNCTION

PIN NAME	Input/Output	FUNCTIONS
$\overline{CS}$	Input	Chip select Chip is enabled when $\overline{CS}$ is at "L" level. Set $\overline{CS}$ to "H" level before executing instructions.
$\overline{CLK}$	Input	Clock Input The DI data is latched at the rising edge of $\overline{CLK}$ . The data is output from DO at the falling edge of $\overline{CLK}$ . $\overline{CLK}$ is enabled when $\overline{CS}$ is at "L" level.
DI	Input	Serial data input The address, command and Data input pin.
DO	Output	Serial data output The data output pin.
$\overline{RST}$	Input	Reset input Reset signal input pin.
$\overline{RDY/BUSY}$	Output	Status output "L" level is output during Program or Chip Erase operation. "H" level is output when Program or Chip Erase operation is completed.
VCC	Power supply	+ 5V
GND		0V (GND)

## OPERATIONAL DESCRIPTION

## 1. INSTRUCTION SET

(1) TC89121

Instruction	Address	Command			Data	
		C0C1	C2	C3		
Read	A0 ~ A6, 0	1	0	0	0	
Program	A0 ~ A6, 0	0	1	1	0	D0 ~ D7
Chip Erase	*****	0	0	1	1	
Busy Monitor	*****	1	0	1	1	
E/W Enable	*****	1	0	0	1	
E/W Disable	*****	1	1	0	1	

\*; don't care

## (2) TC89122

Instruction	Address	Command						Data	
		C0	C1	C2	C3				
Read	A0 ~ A7	1	0	0	0	0	0	0	0
Program	A0 ~ A7	0	1	1	0	0	0	0	D0 ~ D7
Chip Erase	*****	0	0	1	1	0	0	0	0
Busy Monitor	*****	1	0	1	1	0	0	0	0
E/W Enable	*****	1	0	0	1	0	0	0	0
E/W Disable	*****	1	1	0	1	0	0	0	0

\*: don't care

**2. OPERATION METHOD**

Set  $\overline{CS}$  and CLK to "H" level before executing instruction.  $\overline{CS}$  changes to "L" level, then  $\overline{CLK}$  is enabled and operates as the sync signal for serial I/O. The DI data is latched at the rising edge of  $\overline{CLK}$ . The data is output from DO at the falling edge of  $\overline{CLK}$ .

Execute instruction only when RDY/ $\overline{BUSY}$  status signal is "H" level. However Busy Monitor instruction can be executed whenever.

Uses only commands which are included in the Instruction Set listed above.

## (1) Read

Executing Read instruction reads out the memory data at the specified address and outputs it serially from DO.

## (2) Program

Executing Program instruction automatically starts internal rewriting of the memory data at the specified address with the input data.

After Program instruction is input,  $\overline{CS}$  can be set to "H" level even while the internal rewriting process is operating.

## (3) Chip Erase

Executing Chip Erase instruction automatically Starts internal erasing of the memory data at all address.

After Chip Erase instruction is input,  $\overline{CS}$  can be set to "H" level even while the internal erasing process is operating.

## (4) Busy Monitor

Executing Busy Monitor instruction outputs the RDY/ $\overline{BUSY}$  status signal from DO.

"L" level is output during Program or Chip Erase operation. "H" level is output when Program or Chip Erase operation is completed.

The RDY/ $\overline{BUSY}$  status signal is output until  $\overline{CS}$  is switched to "H" level.

## (5) E/W Enable

Executing E/W Enable instruction sets E/W enable mode and enables Program and Chip Erase instructions.

## (6) E/W Disable

Executing E/W Disable instruction sets the E/W disable mode and disables both the Program and Chip Erase instructions. Once E/W disable mode is set, E/W disable mode is held until E/W Enable instruction is executed.

E/W disable mode is set by reset signal input.

**3. CAUTIONS WHEN TURNING THE POWER ON AND OFF**

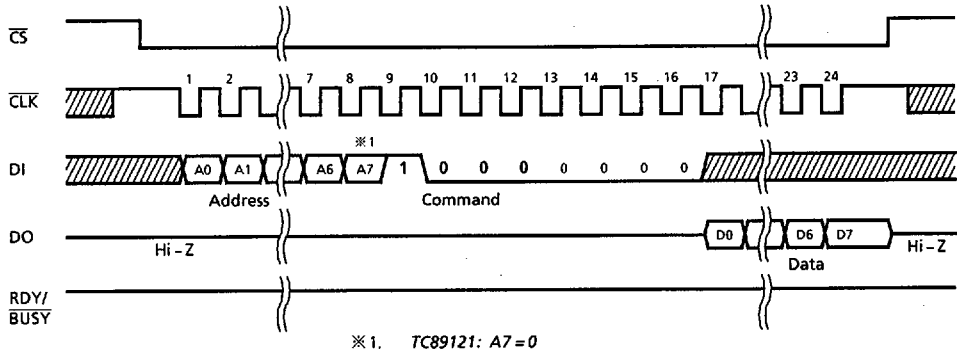
(1) After turning the power on, wait 1ms for warm-up before executing instruction.

(2) Set  $\overline{RST}$  to "L" level when turning the power on and off.

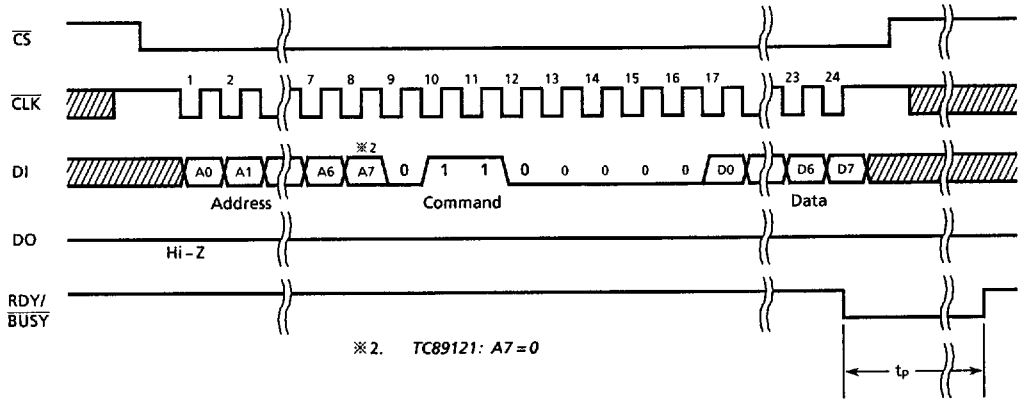
(3) E/W disable mode is set by reset signal input.

4. TIMING DIAGRAMS

(1) Read

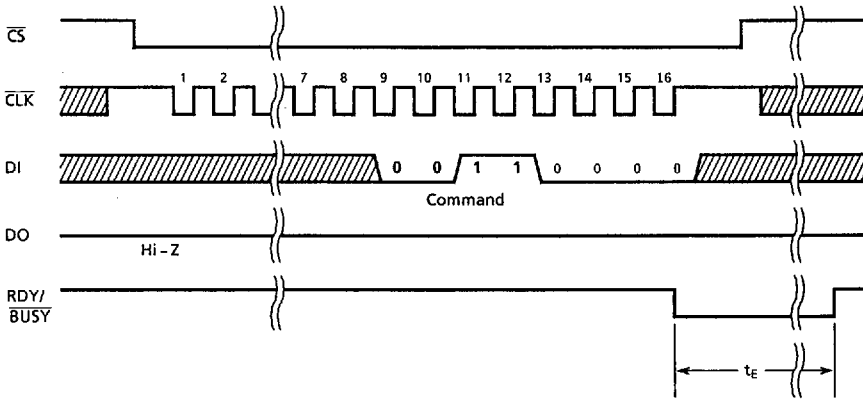


(2) Program

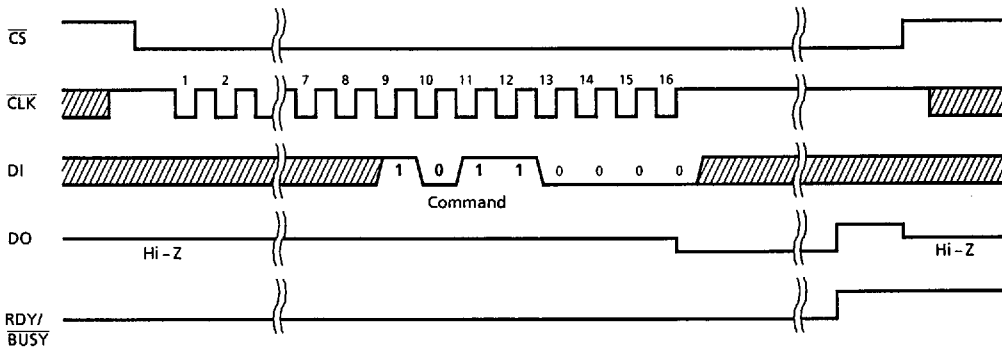


Note.  don't care

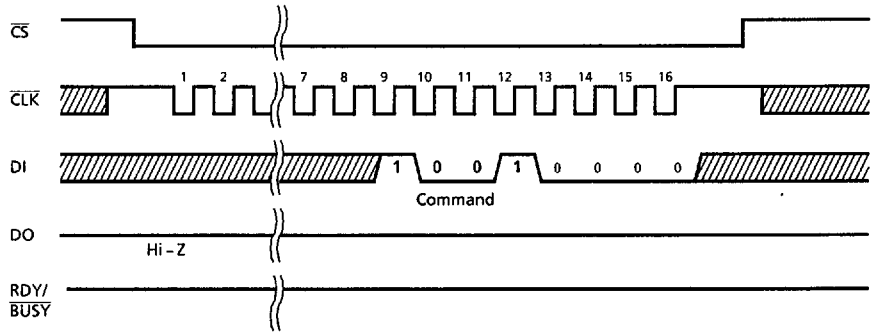
(3) Chip Erase



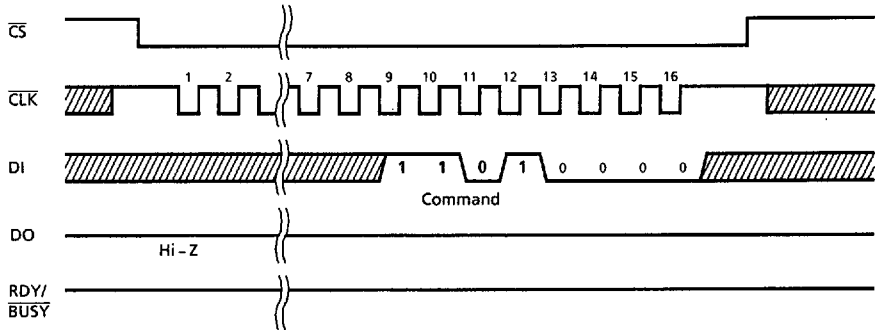
(4) Busy Monitor



(5) E/W Enable



(6) E/W Disable



**ELECTRICAL CHARACTERISTICS**

**ABSOLUTE MAXIMUM RATINGS** (GND = 0V)

PARAMETER	SYMBOL	RATINGS	UNITS
Supply Voltage	$V_{CC}$	- 0.3~7	V
Input Voltage	$V_{IN}$	- 0.3~ $V_{CC} + 0.3$	V
Output Voltage	$V_{OUT}$	- 0.3~ $V_{CC} + 0.3$	V
Power Dissipation	PD	600	mW
Soldering Temperature (time)	Tsld	260 (10sec)	°C
Storage Temperature	Tstg	- 55~125	°C
Operating Temperature	Topr	- 30~70	°C

**RECOMMENDED OPERATING CONDITION** (GND = 0V, Topr = - 30~70°C)

PARAMETER	SYMBOL	CONDITIONS	Min.	Max.	UNITS
Supply Voltage	$V_{CC}$		2.7	5.5	V

**RECOMMENDED OPERATING CONDITION** (GND = 0V, V<sub>CC</sub> = 4.5~5.5V, T<sub>opr</sub> = -30~70°C)

PARAMETER	SYMBOL	PINS	CONDITIONS	Min.	Max.	UNITS
Input Low Voltage	V <sub>IL</sub>		V <sub>CC</sub> = 4.5V	0	0.8	V
Input High Voltage	V <sub>IH1</sub>	$\overline{CS}$ , DI, $\overline{RST}$	V <sub>CC</sub> = 5.5V	2.0	V <sub>CC</sub>	V
	V <sub>IH2</sub>	CLK	V <sub>CC</sub> = 5.5V	3.0	V <sub>CC</sub>	V
Clock Frequency	f <sub>CLK</sub>			0	1	MHz

**D.C. CHARACTERISTICS** (GND = 0V, V<sub>CC</sub> = 4.5~5.5V, T<sub>opr</sub> = -30~70°C)

PARAMETER	SYMBOL	CONDITIONS	Min.	Typ.	Max.	UNITS
Input Current	I <sub>LI</sub>		-	-	± 10	μA
Output Leakage Current	I <sub>LO</sub>		-	-	± 10	μA
Output High Voltage	V <sub>OH1</sub>	V <sub>CC</sub> = 4.5V, I <sub>OH</sub> = -400μA	2.4	-	-	V
Output Low Voltage	V <sub>OL1</sub>	V <sub>CC</sub> = 4.5V, I <sub>OL</sub> = 2.1mA	-	-	0.4	V
Output High Voltage	V <sub>OH2</sub>	I <sub>OH</sub> = -20μA (CMOS Interface)	V <sub>CC</sub> -0.4	-	-	V
Output Low Voltage	V <sub>OL2</sub>	I <sub>OL</sub> = 20μA (CMOS Interface)	-	-	0.4	V
Supply Current	I <sub>CC0</sub>		-	-	500	μA
	I <sub>CCP</sub>	During Program or Chip Erase	-	-	10	mA
	I <sub>CCS</sub>	$\overline{CS}$ = 1 (Except Program or Chip Erase operation)	-	-	10	μA

**A.C. CHARACTERISTICS** (GND = 0V, V<sub>CC</sub> = 4.5~5.5V, T<sub>opr</sub> = -30~70°C)

PARAMETER	SYMBOL	Min.	Max.	UNITS
CLK Frequency	f <sub>CLK</sub>	0	1	MHz
CLK Low Time	t <sub>CKL</sub>	400	-	ns
CLK High Time	t <sub>CKH</sub>	400	-	ns
$\overline{RST}$ Low Time	t <sub>RSW</sub>	1	-	μs
$\overline{RST}$ Input Setup Time	t <sub>RSS</sub>	1	-	μs
CLK Input Setup Time	t <sub>CKS</sub>	250	-	ns
$\overline{CS}$ Input Setup Time	t <sub>CSS</sub>	250	-	ns
DO Output Delay Time ※1	t <sub>ODD1</sub>	-	250	ns
	t <sub>ODD2</sub>	-	500	ns
RDY/ $\overline{BUSY}$ Output Delay Time	t <sub>RBD</sub>	-	250	ns
DI Input Setup Time	t <sub>IDS</sub>	250	-	ns
DI Input Hold Time	t <sub>IDH</sub>	250	-	ns

 ※1 C<sub>L</sub> = 100pF, V<sub>OH</sub> / V<sub>OL</sub> = 2.0V / 0.8V

RECOMMENDED OPERATING CONDITION (GND = 0V, V<sub>CC</sub> = 2.7~3.3V, Topr = -30~70°C)

PARAMETER	SYMBOL	PINS	CONDITIONS	Min.	Max.	UNITS
Input Low Voltage	V <sub>IL</sub>		V <sub>CC</sub> = 2.7V	0	0.45	V
Input High Voltage	V <sub>IH1</sub>	$\overline{CS}$ , DI, $\overline{RST}$	V <sub>CC</sub> = 3.3V	1.6	V <sub>CC</sub>	V
	V <sub>IH2</sub>	$\overline{CLK}$	V <sub>CC</sub> = 3.3V	2.0	V <sub>CC</sub>	V
Clock Frequency	f <sub>CLK</sub>			0	250	KHz

D.C. CHARACTERISTICS (GND = 0V, V<sub>CC</sub> = 2.7~3.3V, Topr = -30~70°C)

PARAMETER	SYMBOL	CONDITIONS	Min.	Typ.	Max.	UNITS
Input Current	I <sub>LI</sub>		-	-	±5	μA
Output Leakage Current	I <sub>LO</sub>		-	-	±5	μA
Output High Voltage	V <sub>OH</sub>	I <sub>OH</sub> = -20 μA (CMOS Interface)	V <sub>CC</sub> - 0.4	-	-	V
Output Low Voltage	V <sub>OL</sub>	I <sub>OL</sub> = 20 μA (CMOS Interface)	-	-	0.4	V
Supply Current	I <sub>CCO</sub>		-	-	100	μA
	I <sub>CCP</sub>	During Program or Chip Erase	-	-	6	mA
	I <sub>CCS</sub>	$\overline{CS}$ = 1 (Except Program or Chip Erase operation)	-	-	5	μA

A.C. CHARACTERISTICS (GND = 0V, V<sub>CC</sub> = 2.7~3.3V, Topr = -30~70°C)

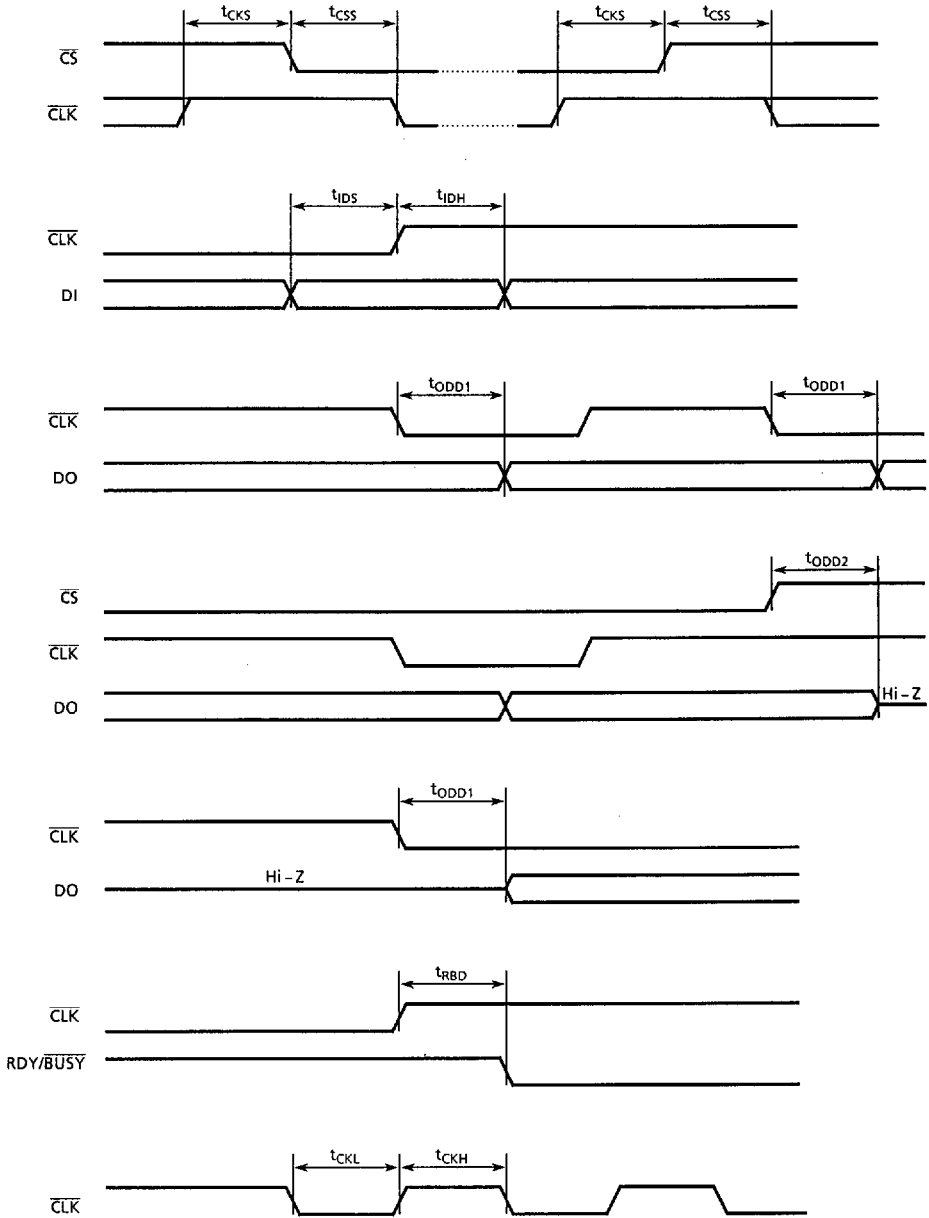
PARAMETER	SYMBOL	Min.	Max.	UNITS
$\overline{CLK}$ Frequency	f <sub>CLK</sub>	0	250	KHz
$\overline{CLK}$ Low Time	t <sub>CKL</sub>	2	-	μs
$\overline{CLK}$ High Time	t <sub>CKH</sub>	2	-	μs
$\overline{RST}$ Low Time	t <sub>R5W</sub>	4	-	μs
$\overline{RST}$ Input Setup Time	t <sub>R5S</sub>	4	-	μs
$\overline{CLK}$ Input Setup Time	t <sub>CKS</sub>	1	-	μs
$\overline{CS}$ Input Setup Time	t <sub>CS5</sub>	1	-	μs
DO Output Delay Time ※1	t <sub>ODD1</sub>	-	1	μs
	t <sub>ODD2</sub>	-	2	μs
RDY/ $\overline{BUSY}$ Output Delay Time	t <sub>RBD</sub>	-	1	μs
DI Input Setup Time	t <sub>IDS</sub>	1	-	μs
DI Input Hold Time	t <sub>IDH</sub>	1	-	μs

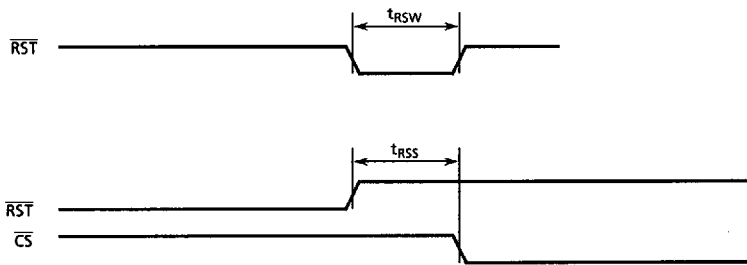
※1 C<sub>L</sub> = 100pF, V<sub>OH</sub> / V<sub>OL</sub> = 1.6V / 0.45V

E<sup>2</sup>PROM CHARACTERISTICS(GND = 0V, V<sub>CC</sub> = 2.7~5.5V, T<sub>opr</sub> = -30~70°C)

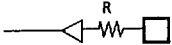
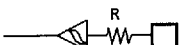
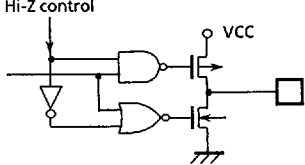
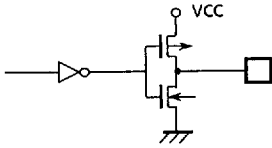
PARAMETER	SYMBOL	CONDITION	Min.	Typ.	Max.	UNITS
Chip Erase Time	t <sub>E</sub>		-	4	10	ms
Program Time	t <sub>p</sub>		-	4	10	ms
Erase/Write Cycle	N <sub>EW</sub>		5 × 10 <sup>4</sup>	3 × 10 <sup>5</sup>	-	cycles
Data Retention Time	t <sub>RET</sub>		10	-	-	years

A.C. CHARACTERISTICS TIMING DIAGRAMS





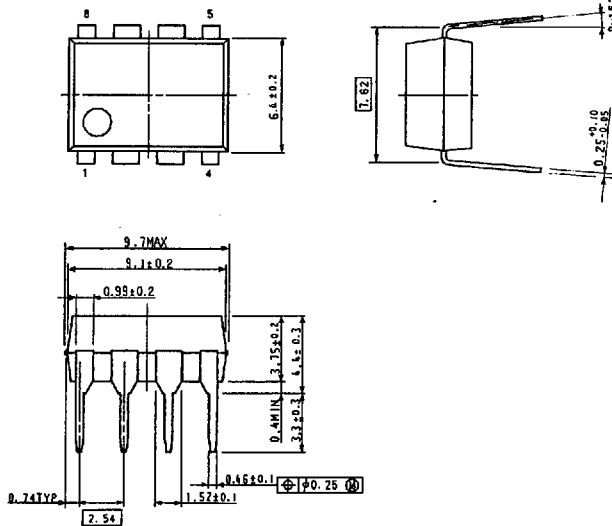
INPUT/OUTPUT CIRCUITRIES

PIN NAME	I/O	INPUT/OUTPUT CIRCUITRY	REMARKS
$\overline{CS}$ $DI$ $RST$	Input		
$\overline{CLK}$	Input		Hysteresis input
$DO$	Output		Initial "Hi-Z"
$RDY/\overline{BUSY}$	Output		Initial "High"

PACKAGE

DIP8-P-300B

UNIT:mm



SOP8-P-225

